


<b>Search Notes</b>  	<b>Application/Control No.</b>  10532049	<b>Applicant(s)/Patent Under Reexamination</b>  OHTANI, YOSHIHIRO
	<b>Examiner</b>  Cehic, Kenan	<b>Art Unit</b>  2416

SEARCHED			
Class	Subclass	Date	Examiner
370	346,449,395.4,343,344, 235, 461	12/4/2007	KC

SEARCH NOTES		
Search Notes	Date	Examiner
Inventorship search	12/7/2007	KC
Consulted with SPE Kwang Yao	12/5/2007	KC
Consulted with SPE Kwang Yao	11/28/2007	KC
IEEEExplorer	12/7/2007	KC
Update search	6/10/2008	kc
Update Search	10/23/2008	kc

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	See Intereference Search printout	10/23/2008	kc

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